

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	1324	29/603.03-603.06,606.ccls.	USPAT; JPO; DERWENT	OR	ON	2005/11/22 09:19
S2	511	360/264.2,264.7,265,265.7-265.9, 266,244.5,244.7.ccls.	USPAT; JPO; DERWENT	OR	ON	2005/11/22 09:19
S3	6	actuator same ((head adj gimbal adj assembly) or HGA) same ((flexible adj printed adj circuit) or FPC)	USPAT; JPO; DERWENT	OR	ON	2005/11/22 09:33
S4	1	(actuator near assembly) same ((head adj gimbal adj assembly) or HGA) same ((flexible adj printed adj circuit) or FPC)	USPAT; JPO; DERWENT	OR	ON	2005/11/22 09:33
S5	14134	(actuator near assembly) or (actuator near coil near assembly)	USPAT; JPO; DERWENT	OR	ON	2005/11/22 09:49
S6	2217	((head adj gimbal adj assembly) or HGA)	USPAT; JPO; DERWENT	OR	ON	2005/11/22 12:01
S7	17580	((flexible adj printed adj circuit) or FPC)	USPAT; JPO; DERWENT	OR	ON	2005/11/22 12:01
S8	23	S5 and S6 and S7	USPAT; JPO; DERWENT	OR	ON	2005/11/22 09:35
S9	0	S1 and S8	USPAT; JPO; DERWENT	OR	ON	2005/11/22 09:35
S11	4	S2 and S8	USPAT; JPO; DERWENT	OR	ON	2005/11/22 09:36
S12	14	S8 and @ad<"20011226"	USPAT; JPO; DERWENT	OR	ON	2005/11/22 12:02
S13	42	wang-Jeffery-L.in. or Kamigama-Takehiro.in. or yuen-Chi-Hung.in. or wu-Kai.in.	USPAT; JPO; DERWENT	OR	ON	2005/11/22 09:46
S14	2	S5 and S6 and S7 and S13	USPAT; JPO; DERWENT	OR	ON	2005/11/22 09:46
S15	5	("5654851" "5862019" "6034843" "6061206" "6246534").PN.	US-PGPUB; USPAT; USOCR	OR	ON	2005/11/22 09:47

S16	8	(US-6851177-\$ or US-6680824-\$ or US-6249404-\$ or US-6036813-\$ or US-6005747-\$ or US-6061206-\$ or US-6034843-\$ or US-5862019-\$).did.	USPAT	OR	ON	2005/11/22 09:48
S17	3	S8 and S16	USPAT; JPO; DERWENT	OR	ON	2005/11/22 09:49
S18	550	(actuator near assembly) or (actuator near coil near assembly)	EPO; JPO	OR	ON	2005/11/22 12:02
S19	212	((head adj gimbal adj assembly) or HGA)	EPO; JPO	OR	ON	2005/11/22 09:49
S20	4494	((flexible adj printed adj circuit) or FPC)	EPO; JPO	OR	ON	2005/11/22 10:41
S21	0	S18 and S19 and S20	EPO; JPO	OR	ON	2005/11/22 09:50
S22	13	S19 and S20	EPO; JPO	OR	ON	2005/11/22 09:50
S23	7	S22 and @ad<"20011226"	USPAT; JPO; DERWENT	OR	ON	2005/11/22 10:42
S24	21	((("3931641") or ("4620251") or ("4724500") or ("4796122") or ("5313353") or ("5654851") or ("6246534") or ("5862019") or ("6043843") or ("6061206"))).PN.	USPAT; USOCR; JPO; DERWENT	OR	OFF	2005/11/22 09:55
S25	4401	S18 or S19 or S20	USPAT; JPO; DERWENT	OR	ON	2005/11/22 10:20
S26	9	S25 and (inject\$3 adj mold\$3)	USPAT; JPO; DERWENT	OR	ON	2005/11/22 10:37
S27	4	((flexible adj printed adj circuit) or FPC) with bracket	EPO; JPO	OR	ON	2005/11/22 10:38
S28	2933	bracket with (metal\$4 or plastic or non-metal\$3)	EPO; JPO	OR	ON	2005/11/22 10:51
S29	0	S27 and S28	EPO; JPO	OR	ON	2005/11/22 10:38
S30	2500	bracket with (metal\$4)	EPO; JPO	OR	ON	2005/11/22 10:40
S31	0	S20 and S30	EPO; JPO	OR	ON	2005/11/22 10:40
S32	537	bracket with (plastic or non-metal\$3)	EPO; JPO	OR	ON	2005/11/22 10:40
S33	0	S20 and S32	EPO; JPO	OR	ON	2005/11/22 10:40
S34	307	((flexible adj printed adj circuit) or FPC) with (metal\$4)	EPO; JPO	OR	ON	2005/11/22 10:41
S35	31296	bracket with (metal\$4 or plastic or non-metal\$3)	US-PGPUB; USPAT; EPO; JPO	OR	ON	2005/11/22 10:42

S36	51	S7 and S35	USPAT; JPO; DERWENT	OR	ON	2005/11/22 10:42
S37	45	S36 and @ad<"20011226"	USPAT; JPO; DERWENT	OR	ON	2005/11/22 10:42
S38	1	(US-5404636-\$.did.	USPAT	OR	ON	2005/11/22 10:51
S39	0	S38 and (metal\$4 or plastic or non-metal\$3)	EPO; JPO	OR	ON	2005/11/22 10:52
S40	0	S38 and (metal\$4 or plastic)	EPO; JPO	OR	ON	2005/11/22 10:52
S41	4	((head adj gimbal adj assembly) or HGA) same (injection adj molding)	USPAT; JPO; DERWENT	OR	ON	2005/11/22 12:01
S42	28	((flexible adj printed adj circuit) or FPC) same (injection adj molding)	USPAT; JPO; DERWENT	OR	ON	2005/11/22 12:01
S43	0	((actuator near assembly) or (actuator near coil near assembly)) same (injection adj molding)	EPO; JPO	OR	ON	2005/11/22 12:02
S44	0	S41 and S42	EPO; JPO	OR	ON	2005/11/22 12:02
S45	2	S41 and @ad<"20011226"	USPAT; JPO; DERWENT	OR	ON	2005/11/22 12:02


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Display Format: ☒ Citation ☐ Citation & Abstract

IEEE JNL. IEEE Journal or Magazine

IEE JNL. IEE Journal or Magazine

IEEE CNF. IEEE Conference Proceeding

IEE CNF. IEE Conference Proceeding

IEEE STD. IEEE Standard

Select Article Information

- ☐ 1. **A study of head stack assembly sensitivity to ESD**
Boone, W.; Himle, J.; Porter, T.; Perry, B.;
Electrical Overstress/Electrostatic Discharge Symposium Proceedings, 1999
28-30 Sept. 1999 Page(s):373 - 379
Digital Object Identifier 10.1109/EOSSED.1999.819086
[AbstractPlus](#) | Full Text: [PDF](#)(456 KB) IEEE CNF
- ☐ 2. **ESD damage of GMR sensors at head stack assembly**
Zeng, R.; Yu Qun; Fenggang Zhao; Hong Tian;
Electrical Overstress/Electrostatic Discharge Symposium Proceedings, 1999
28-30 Sept. 1999 Page(s):380 - 384
Digital Object Identifier 10.1109/EOSSED.1999.819087
[AbstractPlus](#) | Full Text: [PDF](#)(276 KB) IEEE CNF
- ☐ 3. **Evaluation of tribocharging and ESD protection schemes on GMR magne heads during CO₂ jet cleaning**
Vickers, D.; Carradero, D.;
Electrical Overstress/Electrostatic Discharge Symposium Proceedings 2000
26-28 Sept. 2000 Page(s):212 - 216
Digital Object Identifier 10.1109/EOSSED.2000.890048
[AbstractPlus](#) | Full Text: [PDF](#)(288 KB) IEEE CNF
- ☐ 4. **The effect of bonding sequence on GMR ESD protection**
Zhao, F.G.; Rock Tao; Hong Tian;
Electrical Overstress/Electrostatic Discharge Symposium Proceedings 2000
26-28 Sept. 2000 Page(s):202 - 204
Digital Object Identifier 10.1109/EOSSED.2000.890046
[AbstractPlus](#) | Full Text: [PDF](#)(192 KB) IEEE CNF
- ☐ 5. **Threshold of ESD damage to GMR sensor**
Tao, R.; Zhao, F.G.;
Electrical Overstress/Electrostatic Discharge Symposium Proceedings 2000
26-28 Sept. 2000 Page(s):327 - 329
Digital Object Identifier 10.1109/EOSSED.2000.890094
[AbstractPlus](#) | Full Text: [PDF](#)(204 KB) IEEE CNF